

### **ABSTRACT OF THE DISCLOSURE**

Method and apparatus for testing memory cells of a DRAM memory chip arranged together with a nonvolatile memory chip in a multichip memory module. The multichip memory module may be incorporated in an application apparatus, in particular in a mobile telephone or a notebook. One embodiment provides a method for the DRAM memory chip to be subjected to a self-test, during which the functionality of the memory cells is checked, in a time in which the memory cells of the DRAM memory chip are not accessed in an operative operating mode of the application apparatus.